## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | KIM ET AL. | Examiner | Art Unit | Thomas D. Alunkal | 2627 | Page 1 of 1

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0093902	07-2002	Hirai et al.	369/112.17
*	В	US-2002/0071069	06-2002	NAKAGAWA et al.	349/86
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